

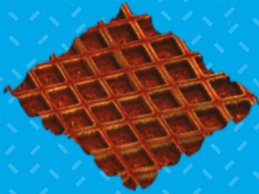


# NenoVision

## Scanning Probe Microscope designed for easy integration into the Electron Microscopes

- 3D visualization of the surface structure
- Complex surface characterization – Topography, Roughness, Magnetic properties, Conductivity, Electrical properties etc.
- Precise SPM tip navigation into the area of the interest by the SEM
- User friendly operation, easy to integration to SEM
- Wide range of SPM imaging modes

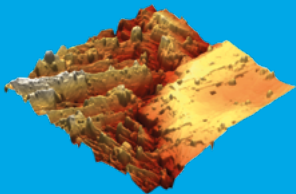
### Explore Variety of Application



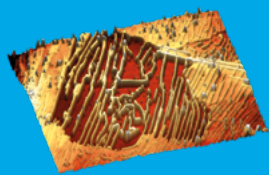
The result of anisotropic wet etching of silicon through line-grid mask, CPEM



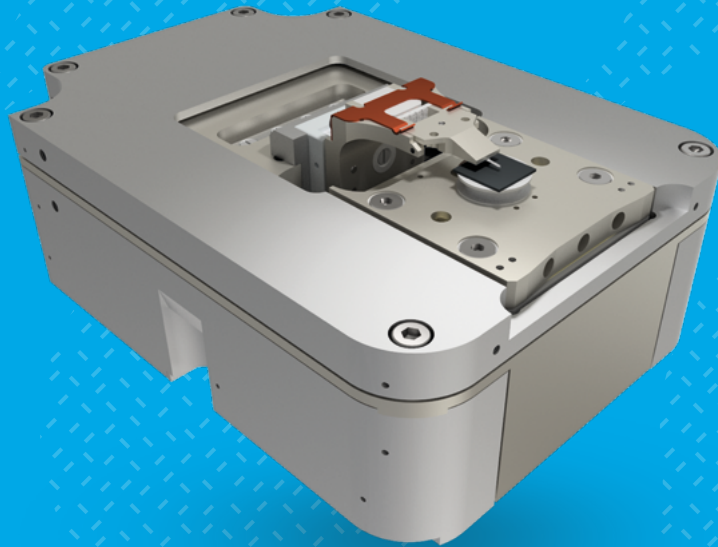
Textured PIN diode on glass substrate – solar cell, CPEM



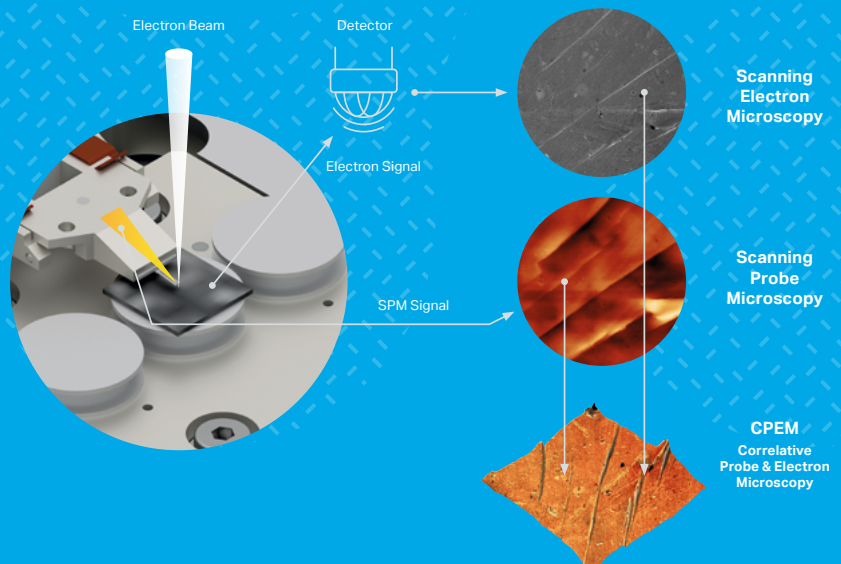
Etched aluminum



Cast-iron



### Explore brand new Correlative Probe and Electron Microscopy technique



# LiteScope™